Docket No.

219625US99DIV

ES PATENT AND TRADEMARK OFFICE

IN RE APPLICATION OF:

JAMAL RAMDANI ET AL

SERIAL NO:

10/076,450

GAU:

FILED:

FEBRUARY 19, 2002

EXAMINER: BAUMEISTER

FOR:

SEMICONDUCTOR STRUCTURE, SEMICONDUCTOR DEVICE, COMMUNICATING DEVICE

INTEGRATED CIRCUIT, AND PROCESS FOR FABRICATING THE SAME

INFORMATION DISCLOSURE STATEMENT UNDER 37 CFR 1.97

ASSISTANT COMMISSIONER FOR PATENTS WASHINGTON, D.C. 20231

SIR:

Applicant(s) wish to disclose the following information.

REFERENCES

- The applicant(s) wish to make of record the references listed on the attached form PTO-1449. Copies of the listed references were submitted in application Serial No. 09/908,888 according to the attached copy of a Granted Petition. This application contains related subject matter.
- A check is attached in the amount required under 37 CFR §1.17(p).

RELATED CASES

- Attached is a list of applicant's pending application(s) or issued patent(s) which may be related to the present application. A copy of the patent(s), together with a copy of the claims and drawings of the pending application(s) is attached along with PTO 1449.
- ☐ A check is attached in the amount required under 37 CFR §1.17(p).

CERTIFICATION

- ☐ Each item of information contained in this information disclosure statement was first cited in a communication from a foreign patent office in a counterpart foreign application not more than three months prior to the filing of this statement.
- No item of information contained in this information disclosure statement was cited in a communication from a foreign patent office in a counterpart foreign application or, to the knowledge of the undersigned, having made reasonable inquiry, was known to any individual designated in 37 CFR §1.56(c) more than three months prior to the filing of this statement.

DEPOSIT ACCOUNT

Please charge any additional fees for the papers being filed herewith and for which no check is enclosed herewith, or credit any overpayment to deposit account number 15-0030. A duplicate copy of this sheet is enclosed.

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Respectfully submitted,

OBLON, SPIVAK, McCLELLAND, MAIER & NEUSTADT, P.C.

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Registration No. 36,379

Tel. (703) 413-3000 Fax. (703) 413-2220 (OSMMN 03/02)

SHEET 1 OF 5

RADEMAR ATTY DOCKET NO. SERIAL NO. Form PTO 1449 U.S. DEPARTMENT OF COMMERCE (Modified) PATENT AND TRADEMARK OFFICE 219625US99DIV 10/076,450 **APPLICANT** LIST OF REFERENCES CITED BY APPLICANT JAMAL RAMDANI ET AL **FILING DATE GROUP** 2815 February 19, 2002 **U.S. PATENT DOCUMENTS EXAMINER** DOCUMENT SUB FILING DATE DATE NAME **CLASS** IF APPROPRIATE INITIAL **CLASS** NUMBER UT 5,528,209 06/18/96 Macdonald et al. UV 5,998,781 12/07/99 Vawter et al. 08/29/00 UW 6,110,813 Ota et al. UX 6,452,232 B1 09/17/02 Adan UY 6,049,110 04/11/00 Koh UZ 5,559,368 09/24/96 Hu et al. VA 6,392,253 B1 05/21/02 Saxena VB 5,585,288 12/17/96 Davis et al. VC 5,268,327 12/07/93 Vernon Nabatame et al. VD 03/06/01 6,198,119 B1 VΕ 09/05/00 6,113,225 Miyata et al. VF 11/16/93 Grudkowski et al. 5.262,659 VG 6,239,012 B1 05/29/01 Kinsman VΗ 6,297,598 10/02/01 Wang et al. VΙ 2002/140012 10/03/02 Droopad VJ 4,866,489 09/12/89 Yokogawa et al. VK 6,080,378 06/27/00 Yokota et al. VL 5,508,554 04/16/96 Takatani et al. VM 6,477,285 B1 11/05/02 Shanley VN 4,695,120 09/22/87 Holder 03/16/99 VO 5,882,948 Jewell VΡ 5,574,589 11/12/96 Feuer et al. VQ 5,510,665 04/23/96 Conley VR 4,804,866 02/14/89 Akiyama vs 5,057,694 10/15/91 Idaka et al. VT 5,635,453 06/03/97 Pique et al. VU 5,719,417 02/17/98 Roeder et al. W 5,998,819 12/07/99 Yokoyama et al. Examiner **Date Considered**

*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

SHEET 2 OF 5

ATTY DOCKET NO. SERIAL NO. Form PTO 1449 (Modified) U.S. DEPARTMENT OF COMMERCE RADEMAR PATENT AND TRADEMARK OFFICE 219625US99DIV 10/076,450 **APPLICANT** LIST OF REFERENCES CITED BY APPLICANT JAMAL RAMDANI ET AL **FILING DATE GROUP** 2815 February 19, 2002 **U.S. PATENT DOCUMENTS** SUB FILING DATE **EXAMINER** DOCUMENT DATE CLASS NAME IF APPROPRIATE INITIAL NUMBER CLASS W 2002/0079576 06/27/02 Seshan VX 5,148,504 09/15/92 Levi et al. VY 2002/0195610 A1 12/26/02 Klosowiak VΖ 5,477,363 12/19/95 Matsuda WA 5,905,571 05/18/99 Butler et al. WB 5,570,226 10/29/96 Ota WC 02/11/92 5,087,829 Ishibashi et al. 09/06/01 Saito WD 2001/0020278 A1 WE 6,496,469 B1 12/17/02 Uchizaki WF 5,679,947 10/21/97 Doi et al. WG 2001/0036142 A1 11/01/01 Kadowaki et al. WH 5.446.719 08/29/95 Yoshida et al. WI 5,831,960 11/03/98 Jiang et al. WJ 5,693,140 12/02/97 McKee et al. WK 6,376,337 B1 04/23/02 Wang et al. WL 4,177,094 12/04/79 Kroon WM 06/01/93 Makki et al. 5,216,359 WN 6,307,996 B1 10/23/01 Nashimoto et al. wo 5,371,621 12/06/94 Stevens WP 2002/0145168 A1 10/10/02 Bojarczuk, Jr et al. WQ 3,617,951 11/02/71 Anderson WR 5,838,053 11/17/98 Bevan et al. ws Wersing et al. 5,684,302 11/04/97 WT 5,959,308 09/28/99 Shichijo et al. WU 5,362,972 11/08/94 Yazawa et al. wv 5,864,171 01/26/99 Yamamoto et al. ww 5,028,563 07/02/91 Feit et al. 08/10/99 WX Domash 5,937,115 Examiner **Date Considered**

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Form PTO 1449 U.S. DEPARTMENT OF COMMERCE (Modified) PATENT AND TRADEMARK OFFICE			ATTY DOCKET NO. 219625US99DIV		SERIAL NO. 10/076,450		
			APPLICANT				
LIST OF	REFE	RENCES CITED BY APP	PLICANT	JAMAL RAMDANI ET AL			
				FILING DATE		GROUP	
				February 19, 2002		2815	
U.S. PATENT DOCUMENTS							
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
	WY	5,878,175	03/02/99	Sonoda et al.			
	wz	4,801,184	01/31/89	Revelli			
	XA	5,140,387	08/18/92	Okazaki et al.			
	XB	5,410,622	04/25/95	Okada et al.			
	хс	6,064,783	05/16/00	Congdon et al.			
	XD	5,772,758	06/30/98	Collins et al.			
	XE	5,666,376	09/09/97	Cheng			
	XF	5,976,953	11/02/99	Zavracky et al.			
	XG	5,578,162	11/26/96	D'Asaro et al.			-
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	ΧI	5,674,813	10/07/97	Nakamura et al.			
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	ХМ						
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Form PTO 1449 U.S. DEPARTMENT OF COMMERCE (Modified)

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		F(DREIGN PATENT DOCUMENTS		·
	DOCUMENT NUMBER	DATE	COUNTRY	TRANS YES	LATION NO
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CB	D EP 0 860 913	08/26/95	EUROPE		
CE	E 5-232307	09/10/93	JAPAN W/ENGLISH ABSTRACT		
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СВ	R 0 600 658	06/08/94	EUROPE		_
CE	S 0 412 002	02/06/91	EUROPE		,
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	KKAO		Solid State Physics"; John Wiley & Sons	s, Inc. Fifth Edition; pp. 415				
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	KKAQ	W. Zhu et al.; "Oriented diamond films grown on nickel substrates"; 320 Applied Physics Letters; 63(1993) September, No. 12, Woodbury, NY, US; pp. 1640-1642						
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	KKAS	Yoshihiro Yokota et al.; "Cathodoluminescence of boron-doped heteroepitaxial diamond films on platinum"; Diamond and Related Materials 8(1999); pp. 1587-1591						
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	KKAW	Lin Li; "Ferroelectric/Superconductor Heterostructures"; Materials Science and Engineering; 29 (2000) pp. 153-181						
	KKAX	L. Fan et al.; "Dynaamic Beam Switching of Vertical-Cavity Surface-Emitting Lasers with Integrated Optical Beam Routers"; IEEE Photonics Technology Letters: Vol. 9, No. 4; April 4, 1997; pp. 505-507						
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